

Search Notes**Application/Control No.**

10/075,035

Examiner

Hien Tran Neckal

Applicant(s)/Patent under Reexamination

LIU ET AL.

Art Unit

1764

SEARCHED

Class	Subclass	Date	Examiner
422	177,180, 171	6/2/2005	HT
55	385.3, 483	6/2/2005	HT
55	484, 499,	6/2/2005	HT
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55	dig.10,	6/2/2005	HT
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updated	search	9/21/06	ASW

**SEARCH NOTES
(INCLUDING SEARCH STRATEGY)**

	DATE	EXMR
East Image class/subclass search / inventor's name search /text search/checked related applications 09/522,152 and 09/851,300	6/2/2005	HT
Updated search	9/21/06	ASW

INTERFERENCE SEARCHED

Class	Subclass	Date	Examiner